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OMB No. 0651-0011 (12/31/86)

Sheet 1 of 3

Form PTO-1449 U.S. Department of Commerce Patent & Trademark Office INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Atty. Docket No. RD-28,645	Serial No. Unassigned
	Applicant(s): Radislav A. Potyrailo James N. Cawse	
	Filing Date Herewith	Group Unassigned

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Examiner * Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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Examiner * Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No
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Examiner * Initial	Title/Author/Publisher/Year Published/Page(s)
W	Ballantine, D. S., Jr., et al., <i>In Acoustic Wave Sensors: Theory, Design, and Physico-Chemical Applications</i> , 1997, Chapter 6, Academic Press: San Diego, CA.
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n	Mark, H. and J. Workman, <i>Statistics in Spectroscopy</i> : Academic Press: San Diego, CA, pp. 263-276 (1991).

EXAMINER m	DATE CONSIDERED 11/03
*Examiner: Initial if referenced considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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W	6,168,914 B1	1/2/2001	Campbell et al.	435	4	12/18/1998
W	6,200,737	3/13/2001	Walt et al.	430	320	8/24/1995

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W	Miller, J. C. and J. N. Miller, <i>Statistics for Analytical Chemistry</i> , Ellis Horwood, New York, NY, pp. 101-139 (1993).
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<i>N</i>	Evans, J.R.G.; Edirisinghe, M.J.; Coveney, P.V.; Eames, J., Combinatorial Searches of Inorganic Materials Using the Ink-Jet Printer: Science, Philosophy and Technology, Journal of the European Ceramics Society, 21 (2001) 2291-2299
<i>N</i>	Prinz, V. Ya; Grutzmacher, D.; Beyer, A.; David, C.; Ketterer, B.; Deckardt, E., A new technique for fabricating three-dimensional micro- and nanostructures of various shapes, Nanotechnology 12 (2001) 399-402
<i>N</i>	Whitesides, G.M., Organic Materials Science, MRS Bulletin, Jan. 2002, Vol. 27, No. 1, pp. 56-65

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